



Power MOSFETS

DATASHEET

LM1FH18NAI8A

N-Channel
Enhancement Mode MOSFET

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Quality Management Systems
ISO 9001:2015 Certificate

LM1FH18NAI8A



N-Channel Enhancement Mode MOSFET

Pin Description

PDFN3.3*3.3	Symbol	Symbol	N-Channel	Unit	
Top View Bottom View		D G S	V _{DSS}	150	V
			R _{DSON} -Max	880	mΩ
			I _D	3.8	A

Product Summary

Feature

- Fast switching speed
 - Reliable and Rugged
 - ROHS Compliant & Halogen-Free
 - 100% UIS and Rg Tested

Applications

- Power Management in DC/DC Converters
 - For POE Power Primary Side Switch or Network application

Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM1FH18NAI8A	PDFN3.3*3.3	Tape & Reel	5000 / Tape & Reel	1FH18 □□□□□

Note : _____ = Lot Code

Absolute Maximum Ratings ($T_J=25^\circ\text{C}$ Unless Otherwise Noted)

Absolute Maximum Ratings (V _G =0 V Unless Otherwise Noted)		N-Channel	Unit
Symbol	Parameter		
V _{DSS}	Drain-Source Voltage	150	V
V _{GSS}	Gate-Source Voltage	±20	
T _J	Maximum Junction Temperature	150	°C
T _{STG}	Storage Temperature Range	-55 to 150	°C
I _S	Diode Continuous Forward Current	T _C =25°C 11.4	A
I _{DM} ^①	Pulse Drain Current Tested	T _C =25°C 9.4	A
I _D	Continuous Drain Current	T _C =25°C T _C =100°C 3.8 2.4	A
P _D	Maximum Power Dissipation	T _C =25°C T _C =100°C 12.5 5	W
I _D	Continuous Drain Current	T _A =25°C T _A =70°C 1.3 1.1	A
P _D	Maximum Power Dissipation	T _A =25°C T _A =70°C 1.6 1.0	W
I _{AS} ^②	Avalanche Current, Single pulse	L=0.1mH L=0.5mH 2.8 1.8	A
E _{AS} ^②	Avalanche Energy, Single pulse	L=0.1mH L=0.5mH 0.4 0.8	mJ

Thermal Characteristics

Symbol	Parameter	Rating	Unit	
R_{JC}	Thermal Resistance-Junction to Case	Steady State	10	°C/W
$R_{JA}^{(3)}$	Thermal Resistance-Junction to Ambient	Steady State	80	°C/W

Note ① : Max. current is limited by junction temperature

Note ② : UIIS tested and pulse width are limited by maximum junction temperature 150°C

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz.

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N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Electrical Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_{\text{DS}}=250\mu\text{A}$	150	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=120\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	1	μA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_{\text{DS}}=250\mu\text{A}$	1	2	3	V
I_{GSS}	Gate Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
$R_{\text{DS(ON)}}^{\circledast}$	Drain-Source On-state Resistance	$V_{\text{GS}}=10\text{V}$, $I_{\text{DS}}=0.5\text{A}$	-	700	880	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$, $I_{\text{DS}}=0.5\text{A}$	-	720	940	
g_{fs}	Forward Transconductance	$V_{\text{DS}}=10\text{V}$, $I_{\text{DS}}=0.1\text{A}$	-	0.7	-	S
Dynamic Characteristics [®]						
R_{G}	Gate Resistance	$V_{\text{GS}}=0\text{V}$, $V_{\text{DS}}=0\text{V}$, Freq.=1MHz	-	4.5	-	Ω
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$, $V_{\text{DS}}=40\text{V}$, Freq.=1MHz	-	222	-	pF
C_{oss}	Output Capacitance		-	7.6	-	
C_{rss}	Reverse Transfer Capacitance		-	3	-	
$t_{\text{d(ON)}}$	Turn-on Delay Time	$V_{\text{GS}}=10\text{V}$, $V_{\text{DS}}=75\text{V}$, $I_{\text{D}}=1\text{A}$, $R_{\text{GEN}}=6\Omega$	-	1	-	nS
t_{r}	Turn-on Rise Time		-	19.3	-	
$t_{\text{d(OFF)}}$	Turn-off Delay Time		-	11.2	-	
t_{f}	Turn-off Fall Time		-	19.2	-	
Q_{g}	Total Gate Charge	$V_{\text{GS}}=4.5\text{V}$, $V_{\text{DS}}=75\text{V}$ $I_{\text{D}}=1\text{A}$	-	3.1	-	nC
Q_{g}	Total Gate Charge	$V_{\text{GS}}=10\text{V}$, $V_{\text{DS}}=75\text{V}$, $I_{\text{D}}=1\text{A}$	-	6.4	-	
Q_{gs}	Gate-Source Charge		-	0.98	-	
Q_{gd}	Gate-Drain Charge		-	0.97	-	
Source-Drain Characteristics						
$V_{\text{SD}}^{\circledast}$	Diode Forward Voltage	$I_{\text{SD}}=0.5\text{A}$, $V_{\text{GS}}=0\text{V}$	-	0.75	1.1	V
t_{rr}	Reverse Recovery Time	$I_{\text{F}}=0.5\text{A}$, $V_{\text{R}}=0\text{V}$	-	18	-	nS
Q_{rr}	Reverse Recovery Charge	$dI_{\text{F}}/dt=100\text{A}/\mu\text{s}$	-	9	-	nC

Note ④ : Pulse test (pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$).

Note ⑤ : Guaranteed by design, not subject to production testing.

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N-Channel Typical Characteristics

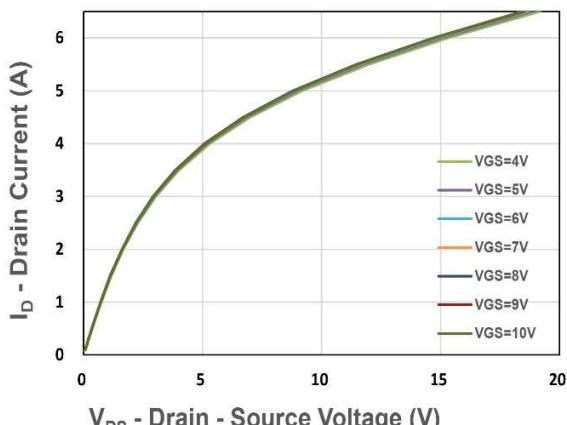


Figure 1. Output Characteristics

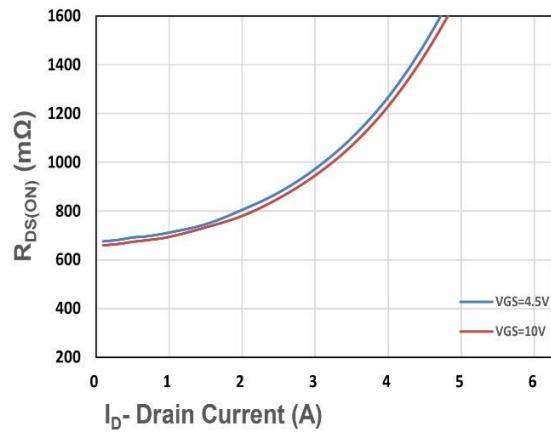


Figure 2. On-Resistance vs. ID

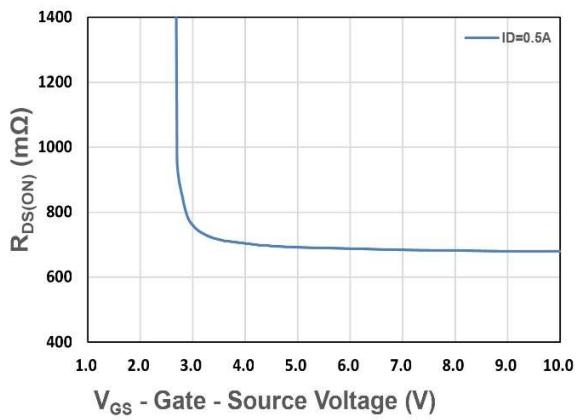


Figure 3. On-Resistance vs. VGS

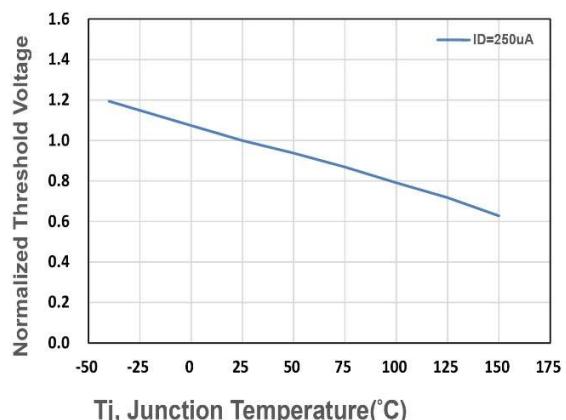


Figure 4. Gate Threshold Voltage

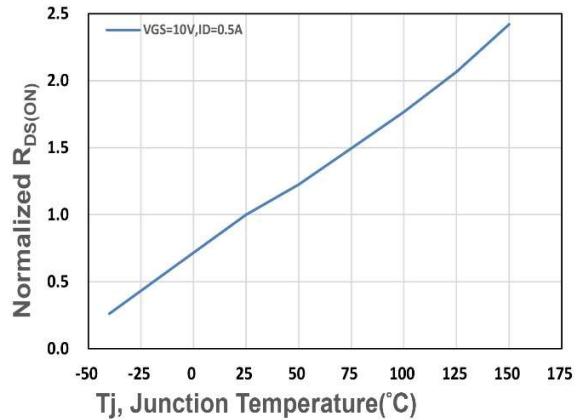


Figure 5. Drain-Source On Resistance

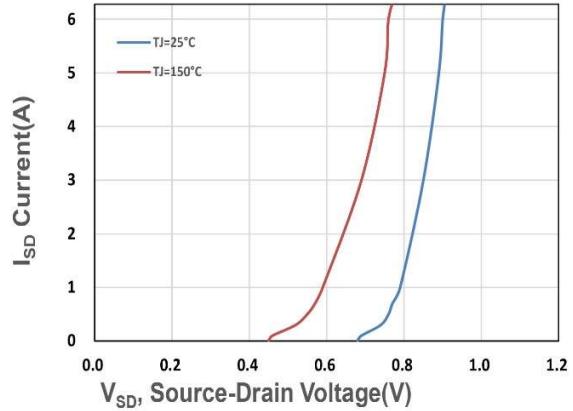


Figure 6. Source-Drain Diode Forward

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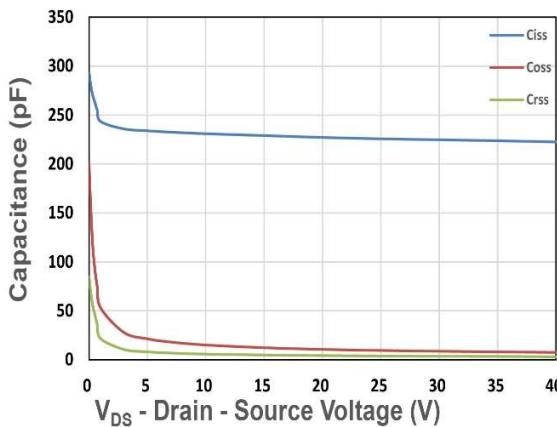


Figure 7. Capacitance

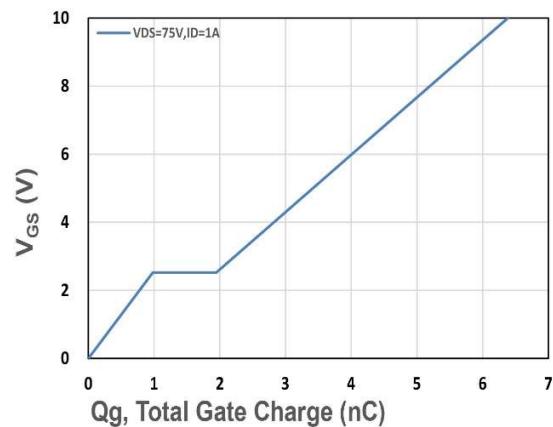


Figure 8. Gate Charge Characteristics

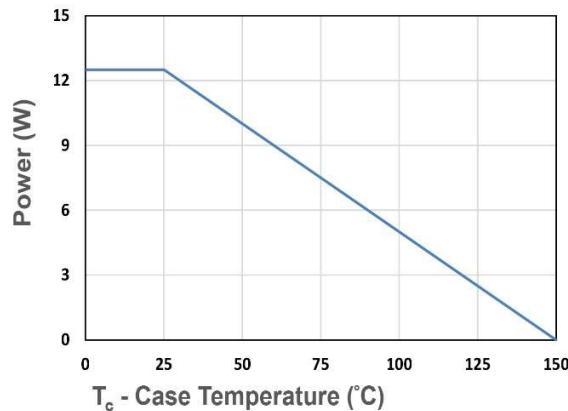


Figure 9. Power Dissipation

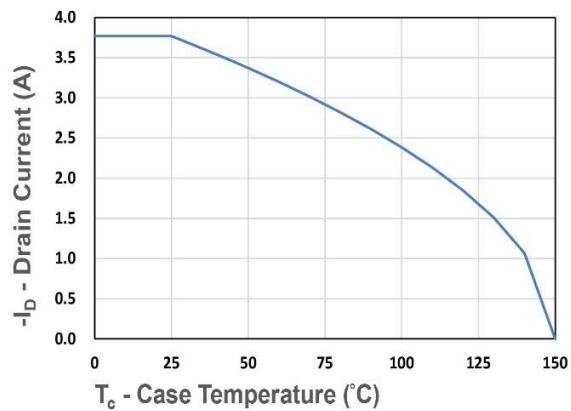


Figure 10. Drain Current

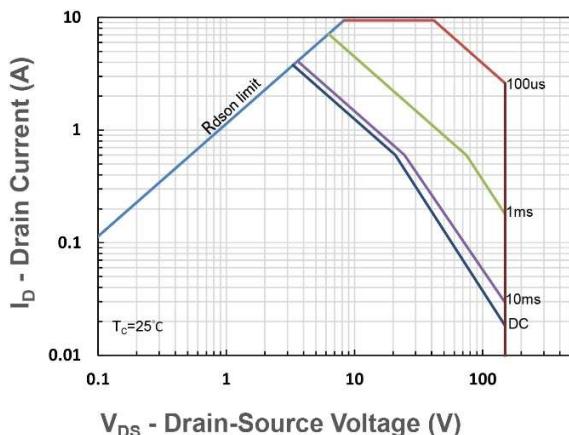


Figure 11. Safe Operating Area

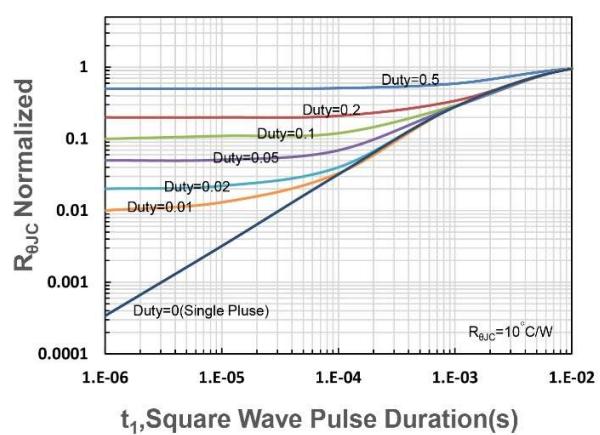


Figure 12. R_{θJC} Transient Thermal Impedance